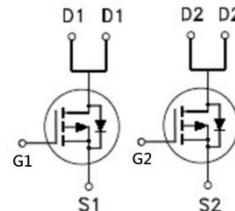


**NIKO-SEM**
**Dual P-Channel Enhancement Mode  
Field Effect Transistor**
**PV551DA**  
**SOP-8**  
**Halogen-free & Lead-Free**
**PRODUCT SUMMARY**

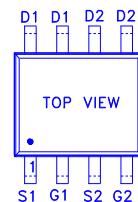
$V_{(BR)DSS}$	$R_{DS(ON)}$	$I_D$
-30V	20mΩ	-8A

**Features**

- Pb-Free, Halogen Free and RoHS compliant.
- Low  $R_{DS(on)}$  to Minimize Conduction Losses.
- Ohmic Region Good  $R_{DS(on)}$  Ratio.
- Optimized Gate Charge to Minimize Switching Losses.

**Applications**

- Protection Circuits Applications.
- Logic/Load Switch Circuits Applications.


G : GATE  
D : DRAIN  
S : SOURCE

100% UIS Tested  
100% Rg Tested
**ABSOLUTE MAXIMUM RATINGS ( $T_A = 25^\circ\text{C}$  Unless Otherwise Noted)**

PARAMETERS/TEST CONDITIONS		SYMBOL	LIMITS	UNITS
Drain-Source Voltage		$V_{DS}$	-30	V
Gate-Source Voltage		$V_{GS}$	$\pm 25$	V
Continuous Drain Current	$T_A = 25^\circ\text{C}$	$I_D$	-8	A
	$T_A = 70^\circ\text{C}$		-6.6	
Pulsed Drain Current <sup>1</sup>		$I_{DM}$	-40	
Avalanche Current		$I_{AS}$	-23	
Avalanche Energy	$L = 0.1\text{mH}$	$E_{AS}$	26.4	mJ
Power Dissipation <sup>3</sup>	$T_A = 25^\circ\text{C}$	$P_D$	2	W
	$T_A = 70^\circ\text{C}$		1.3	
Junction & Storage Temperature Range		$T_j, T_{stg}$	-55 to 150	°C

**THERMAL RESISTANCE RATINGS**

THERMAL RESISTANCE		SYMBOL	TYPICAL	MAXIMUM	UNITS
Junction-to-Ambient <sup>2</sup>	$t \leq 10\text{s}$	$R_{\theta JA}$	56	89	°C / W
Junction-to-Ambient <sup>2</sup>	Steady-State	$R_{\theta JA}$			
Junction-to-Case	Steady-State	$R_{\theta JC}$			

<sup>1</sup>Pulse width limited by maximum junction temperature.

<sup>2</sup>The value of  $R_{\theta JA}$  is measured with the device mounted on 1in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with  $T_A = 25^\circ\text{C}$ .

<sup>3</sup>The Power dissipation is based on  $R_{\theta JA}$   $t \leq 10\text{s}$  value.

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**ELECTRICAL CHARACTERISTICS ( $T_J = 25^\circ\text{C}$ , Unless Otherwise Noted)**

PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNIT
			MIN	TYP	MAX	
<b>STATIC</b>						
Drain-Source Breakdown Voltage	$V_{(\text{BR})\text{DSS}}$	$V_{\text{GS}} = 0\text{V}, I_D = -250\mu\text{A}$	-30			V
Gate Threshold Voltage	$V_{\text{GS}(\text{th})}$	$V_{\text{DS}} = V_{\text{GS}}, I_D = -250\mu\text{A}$	-1	-1.65	-3	
Gate-Body Leakage	$I_{\text{GSS}}$	$V_{\text{DS}} = 0\text{V}, V_{\text{GS}} = \pm 25\text{V}$			$\pm 100$	nA
Zero Gate Voltage Drain Current	$I_{\text{DSS}}$	$V_{\text{DS}} = -30\text{V}, V_{\text{GS}} = 0\text{V}$			-1	$\mu\text{A}$
		$V_{\text{DS}} = -30\text{V}, V_{\text{GS}} = 0\text{V}, T_J = 55^\circ\text{C}$			-10	
Drain-Source On-State Resistance <sup>1</sup>	$R_{\text{DS}(\text{ON})}$	$V_{\text{GS}} = -4.5\text{V}, I_D = -8\text{A}$		26	35	$\text{m}\Omega$
		$V_{\text{GS}} = -10\text{V}, I_D = -8\text{A}$		17	20	
Forward Transconductance <sup>1</sup>	$g_{\text{fs}}$	$V_{\text{DS}} = -5\text{V}, I_D = -8\text{A}$		19		S

**DYNAMIC**

Input Capacitance	$C_{\text{iss}}$	$V_{\text{GS}} = 0\text{V}, V_{\text{DS}} = -15\text{V}, f = 1\text{MHz}$	1008		pF
Output Capacitance	$C_{\text{oss}}$		156		
Reverse Transfer Capacitance	$C_{\text{rss}}$		120		
Gate Resistance	$R_g$	$V_{\text{GS}} = 0\text{V}, V_{\text{DS}} = 0\text{V}, f = 1\text{MHz}$	7.8		$\Omega$
Total Gate Charge <sup>2</sup>	$Q_g$	$V_{\text{DS}} = -15\text{V}, V_{\text{GS}} = -10\text{V}, I_D = -8\text{A}$	19.8		nC
Gate-Source Charge <sup>2</sup>	$Q_{\text{gs}}$		2.6		
Gate-Drain Charge <sup>2</sup>	$Q_{\text{gd}}$		4.6		
Turn-On Delay Time <sup>2</sup>	$t_{\text{d}(\text{on})}$	$V_{\text{DD}} = -15\text{V}$ $I_D \geq -8\text{A}, V_{\text{GS}} = -10\text{V}, R_{\text{GEN}} = 6\Omega$	7.5		nS
Rise Time <sup>2</sup>	$t_r$		48		
Turn-Off Delay Time <sup>2</sup>	$t_{\text{d}(\text{off})}$		48		
Fall Time <sup>2</sup>	$t_f$		74		

**SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS ( $T_J = 25^\circ\text{C}$ )**

Continuous Current	$I_S$				-1.5	A
Forward Voltage <sup>1</sup>	$V_{\text{SD}}$	$I_F = -8\text{A}, V_{\text{GS}} = 0\text{V}$			-1.3	V
Reverse Recovery Time	$t_{\text{rr}}$	$I_F = -8\text{A}, dI/dt = 100\text{A}/\mu\text{s}$		8.5		nS
Reverse Recovery Charge	$Q_{\text{rr}}$			2.2		nC

<sup>1</sup>Pulse test : Pulse Width  $\leq 300\ \mu\text{sec}$ , Duty Cycle  $\leq 2\%$ .

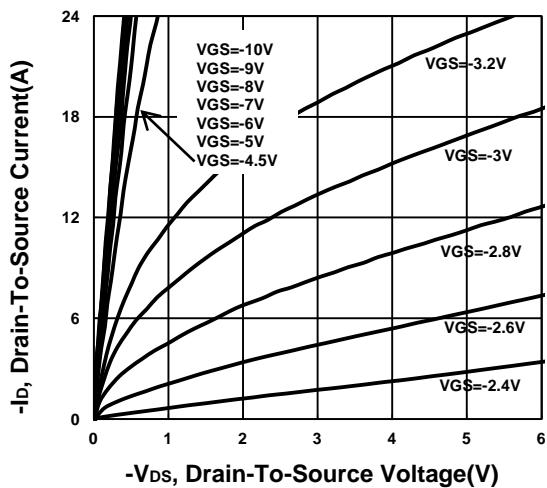
<sup>2</sup>Independent of operating temperature.

**NIKO-SEM**

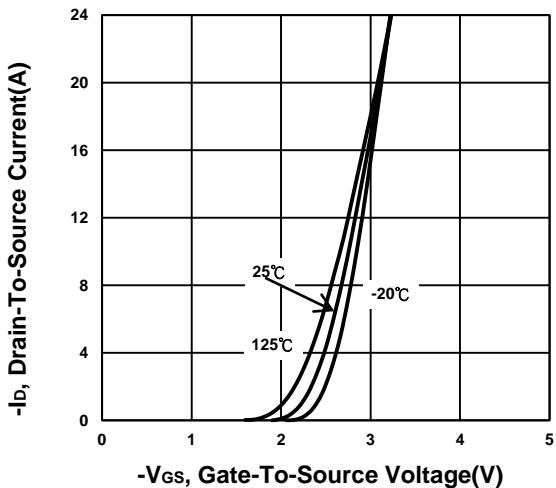
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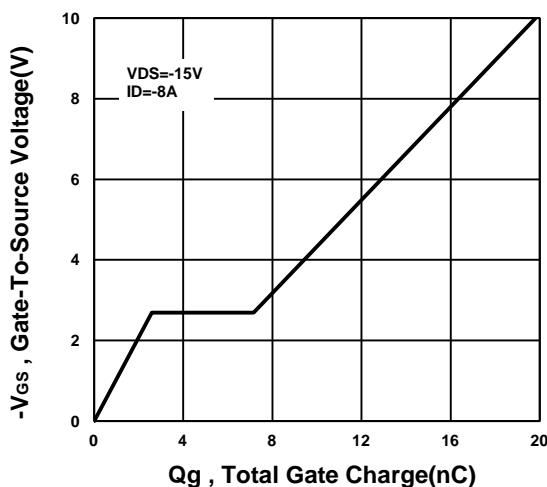
### Output Characteristics



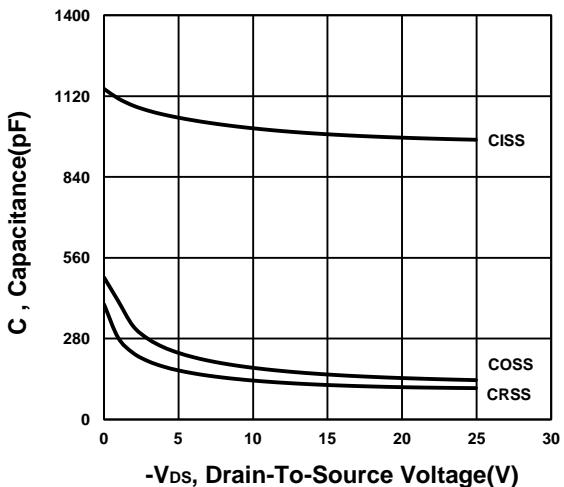
### Transfer Characteristics



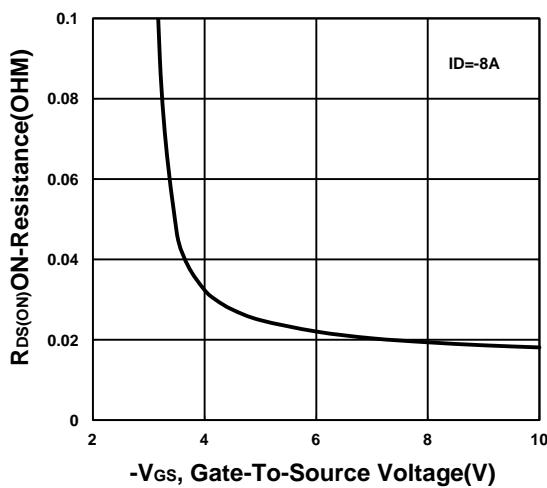
### Gate charge Characteristics



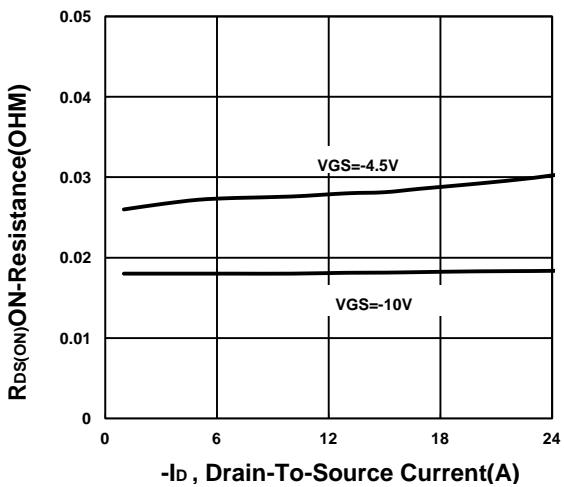
### Capacitance Characteristic



### On-Resistance VS Gate-To-Source Voltage



### On-Resistance VS Drain Current



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